MONASH University

MONASH CENTRE FOR ELECTRON MICROSCOPY

SEMINAR

Quantitative and Qualitative Aberration Corrected STEM

Dr Andrew Bleloch

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Thursday 21 February 2008, 11.00 a.m. – 12 noon
Science Lecture Theatre S11, Bldg 25

Abstract

Aberration correctors in transmission electron microscopy have necessitated a re-appraisal of many hitherto well understood concepts like resolution and detection thresholds. An example of characterizing the electron probe in a STEM instrument will be presented followed by examples of applications of aberration corrected STEM and EELS with an emphasis on single atom sensitivity. These will include studies of the presence of gold atoms in silicon nano-wires and graphene.

Convenor: Dr. Joanne Etheridge

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Visitors are most welcome: Please note that there is a designated Visitors Car Park (N1) clearly ground-marked by white paint and tickets, at a cost of $1.4/hour for up to 3 hours, available from a dispensing machine. This high-rise carpark is located on the following Clayton Campus Map, Ref. B2.

Printable version of the Clayton campus map (pdf 833 kb) (Please right click to open link)